# MSKSEMI















**ESD** 

TVS

TSS

MOV

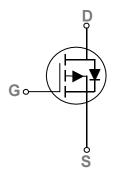
GDT

**PLED** 

# Broduct data sheet

# **SOT-323 Pin Configuration**





# **Features**

- -20V,-1.5A,  $RDS(ON) = 90m\Omega@VGS = -4.5V$
- Improved dv/dt capability
- Fast switching
- Green Device Available

# **Applications**

- Notebook
- Load Switch
- Battery Protection
- Hand-held Instruments

BVDSS	RDSON	ID
-20V	$90$ m $\Omega$	-1.5A

# **Absolute Maximum Ratings** Tc=25℃ unless otherwise noted

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	-20	V
V <sub>GS</sub>	Gate-Sou₁ce Voltage	± 12	V
1-	Drain Current – Continuous (Tc=25℃)		Α
l <sub>D</sub>	Drain Current – Continuous (Tc=100°C)	-0.95	Α
I <sub>DM</sub>	Drain Current – Pulsed <sup>1</sup>	-6	Α
D <sub>-</sub>	Power Dissipation (T <sub>C</sub> =25°C)	312	mW
P <sub>D</sub> Power Dissipation – Derate above 25°C		2.5	mW/°C
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

## **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction to ambient		400	°C/W



# **Electrical Characteristics** (T<sub>J</sub>=25 ℃, unless otherwise noted)

## **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA		-20			V
BV <sub>DSS</sub> T <sub>J</sub>	T <sub>J</sub> BV <sub>DSS</sub> Temperature Coefficient Reference to 25℃, I <sub>D</sub> =-1mA			-0.01		V/°C
	Dunin Course Leakens Cumant	V <sub>DS</sub> =-20V , V <sub>GS</sub> =0V , T <sub>J</sub> =25			-1	uA
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =-16V , V <sub>GS</sub> =0V , T <sub>J</sub> =125			-10	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> 12V , V <sub>DS</sub> =0V			100	nA

## **On Characteristics**

R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-1A		90	110	
		V <sub>GS</sub> =-2.5V , I <sub>D</sub> =-1A		110	135	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	\/=\/ .   = 250uA	-0.3	-0.6	-1.0	V
$V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS}=V_{DS}$ , $I_D=-250uA$		3		mV/∘c
gfs	Forward Transconductance	V <sub>DS</sub> =-10V , I <sub>S</sub> =-1A		2.2		S

# **Dynamic and switching Characteristics**

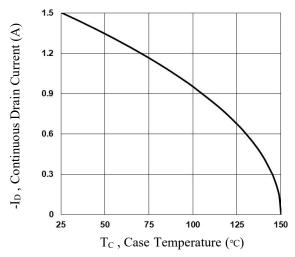
Qg	Total Gate Charge <sup>2, 3</sup>			4.8	8	
Q <sub>gs</sub>	Gate-Source Charge <sup>2, 3</sup>	$V_{DS}$ =-10V , $V_{GS}$ =-4.5V , $I_{D}$ =-1A		0.5	1	nC
$Q_{gd}$	Gate-Drain Charge <sup>2, 3</sup>			1.9	4	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2,3</sup>			3.5	7	
Tr	Rise Time <sup>2,3</sup>	$V_{DD}$ =-10V , $V_{GS}$ =-4.5V , $R_{G}$ =25 $\Omega$		12.6	24	
$T_{d(off)}$	Turn-Off Delay Time <sup>2,3</sup>	I <sub>D</sub> =-1A		32.6	62	ns
T <sub>f</sub>	Fall Time <sup>2, 3</sup>			8.4	16	
C <sub>iss</sub>	Input Capacitance			350	510	
Coss	C <sub>oss</sub> Output Capacitance V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , F=1M			65	95	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			50	75	

# **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
Is	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V . Force Current			-1.5	Α
Іѕм	Pulsed Source Current	VG-VD-UV , Force Current			-3	Α
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25℃			-1	V

- 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- The data tested by pulsed , pulse width  $\leq 300 \text{us}$  , duty cycle  $\leq 2\%$ . 2.
- Essentially independent of operating temperature.





Continuous Drain Current vs. Tc

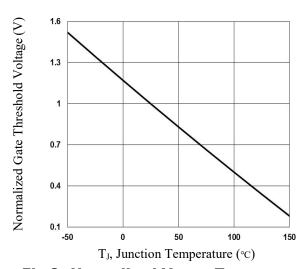
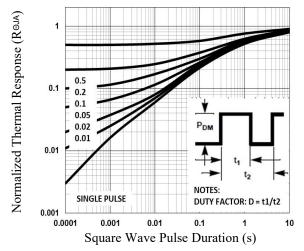


Fig.3 Normalized V<sub>th</sub> vs. T<sub>J</sub>



**Normalized Transient Response** 

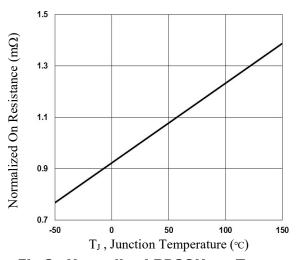
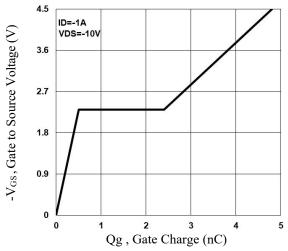


Fig.2 Normalized RDSON vs. T<sub>J</sub>



**Gate Charge Waveform** Fig.4

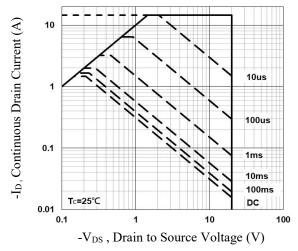
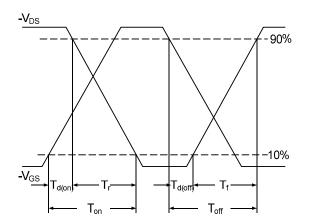


Fig.6 Maximum Safe Operation Area





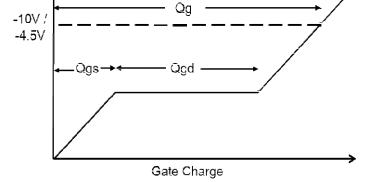
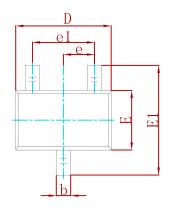


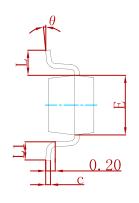
Fig.7 Switching Time Waveform

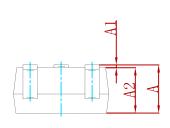
Fig.8 Gate Charge Waveform



# **PACKAGE MECHANICAL DATA**

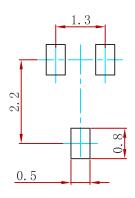






Cumbal	Dimensions	Dimensions In Millimeters		s In Inches
Symbol	Min	Max	Min	Max
Α	0.900	1.100	0.035	0.043
A1	0.000	0.100	0.000	0.004
A2	0.900	1.000	0.035	0.039
b	0.200	0.400	0.008	0.016
С	0.080	0.150	0.003	0.006
D	2.000	2.200	0.079	0.087
Е	1.150	1.350	0.045	0.053
E1	2.150	2.450	0.085	0.096
е	0.65	0 TYP	0.026	3 TYP
e1	1.200	1.400	0.047	0.055
L	0.52	5 REF	0.02	I REF
L1	0.260	0.460	0.010	0.018
θ	0°	8°	0°	8°

# **Suggested Pad Layout**



- 1. Controlling dimension:in millimeters.
- 2.General tolerance:±0.05mm.
- 3. The pad layout is for reference purposes only.

# **REEL SPECIFICATION**

P/N	PKG	QTY
NTS2101PT1G-MS	SOT-323	3000



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